

01.03.2017

Accurate Reconstruction of X-Ray Spectra in CT from Simple Transmission Measurements

Carsten Leinweber, Joscha Maier,
and Marc Kachelrieß

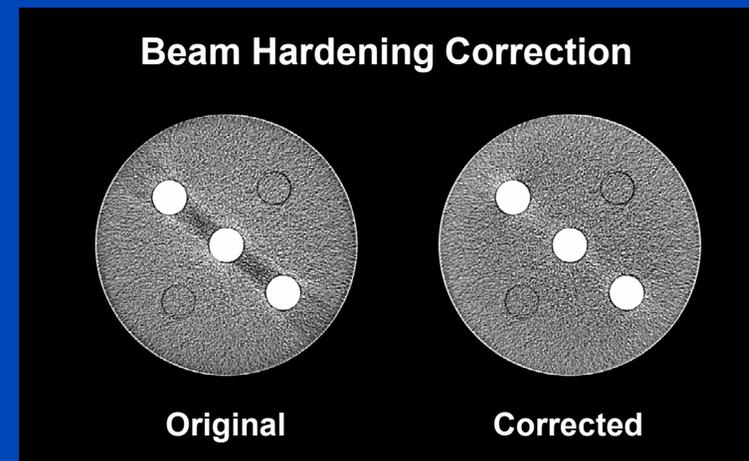
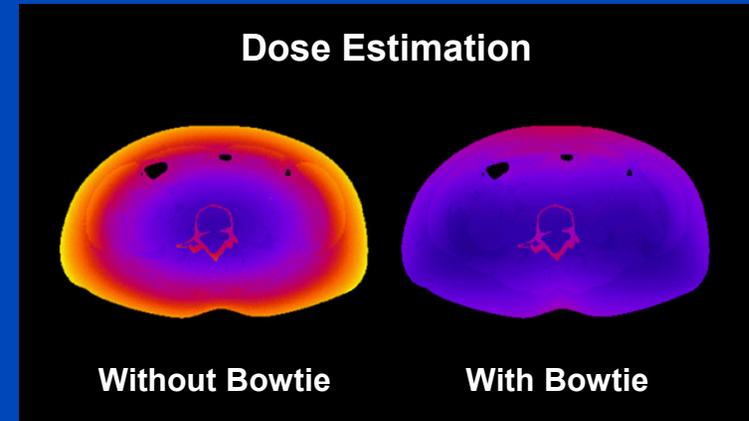
German Cancer Research Center (DKFZ), Heidelberg, Germany



DEUTSCHES
KREBSFORSCHUNGSZENTRUM
IN DER HELMHOLTZ-GEMEINSCHAFT

Introduction

- CT applications that require accurate knowledge of the emitted or detected spectrum:
 - Organ dose estimation
 - Beam hardening correction
 - Dual energy decomposition
 - K-edge imaging
 - Quantitative perfusion measurements
 - ...
- Existing methods:
 - Semi-analytic models
 - Monte-Carlo simulation
 - Spectroscopy
 - Compton scattering
 - **Transmission measurements (direct, simple, no extra hardware)**
 - ...



Spectrum Reconstruction from Transmission Measurements

- Lambert-Beer law:

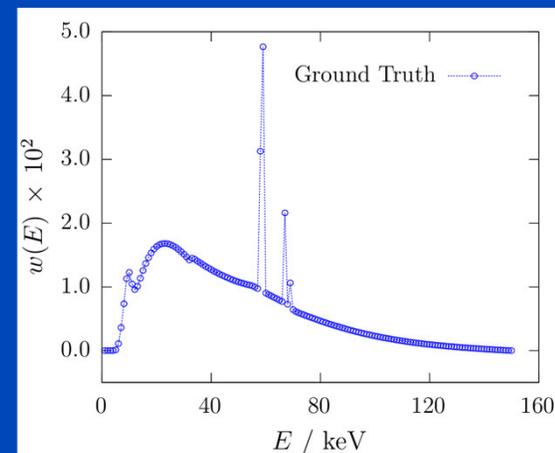
$$\tau_m = \frac{N_m}{N_0} = \sum_{b=1}^B e^{-\mu_{mb} d_m} w_b$$

- Problem:

“Given τ for different (known) combinations of $\mu(E)$ and d , reconstruct $w(E)$.”

- Methods:

- Few parameter modelling
- Neural networks
- Expectation maximization (EM)
- Truncated singular value decomposition (TSVD)
- New: PTSVD



Materials and Methods

Truncated Singular Value Decomposition (TSVD)

- Discretized Lambert-Beer law in matrix notation:

$$\tau_m = \sum_{b=1}^B a_{mb} w_b \longrightarrow \boldsymbol{\tau} = \mathbf{A} \cdot \mathbf{w}$$

- Minimize the least square difference

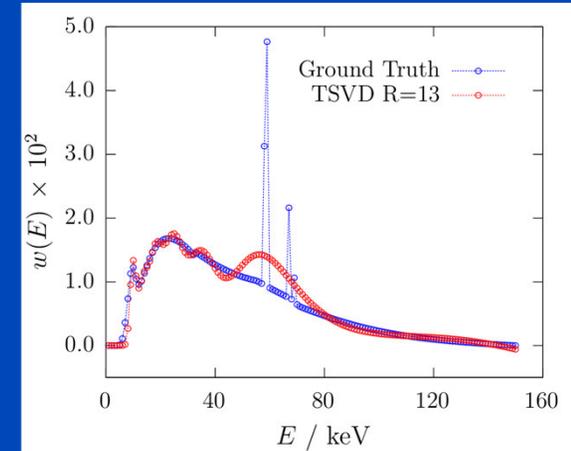
$$\mathbf{w} = \arg \min_{\mathbf{w}} \|\mathbf{A} \cdot \mathbf{w} - \boldsymbol{\tau}\|_2^2 \longrightarrow \mathbf{w} = \mathbf{A}^+ \cdot \boldsymbol{\tau}$$

- Calculation of the pseudo-inverse \mathbf{A}^+
 - Decompose \mathbf{A} into orthonormal basis with help of SVD:

$$\mathbf{A} = \sum_{b=1}^B \mathbf{u}_b \cdot s_b \mathbf{v}_b^T$$

- Truncate \mathbf{A}^+ to the highest R singular values:

$$\mathbf{w} = \sum_{b=1}^R \left(\mathbf{v}_b \cdot \frac{\mathbf{u}_b^T}{s_b} \right) \cdot \boldsymbol{\tau} \quad R \leq B$$



Prior Truncated Singular Value Decomposition (PTSVD)

- Minimize the weighted least square difference with help of TSVD to obtain the low frequent solution from range:

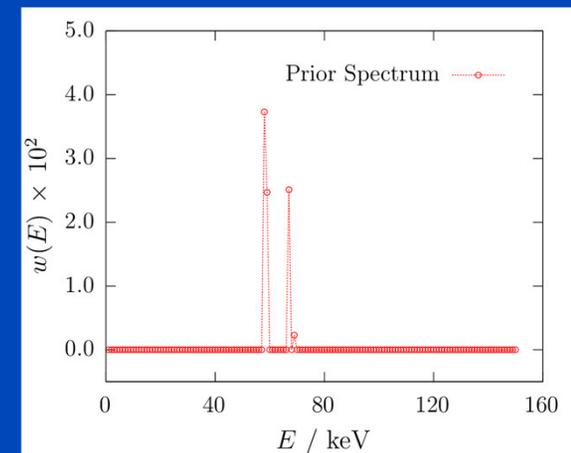
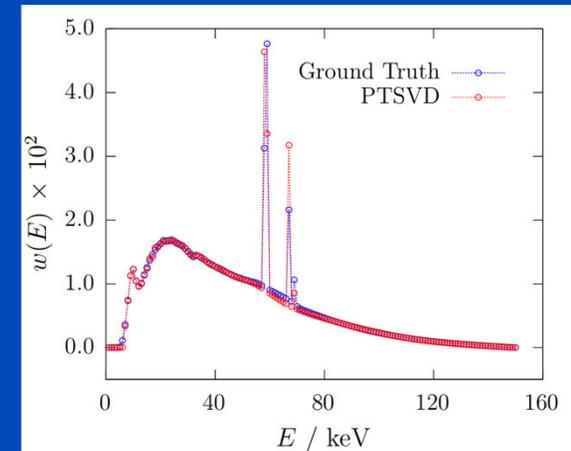
$$w_R = \arg \min_w \|A \cdot w - \tau\|_W^2 \quad \text{with} \quad W = \text{Cov}(\tau, \tau)^{-1}$$

- Calculate a solution from null space that represents the high frequency components (here: characteristic peaks):

$$w_N = \sum_{b=R+1}^B (v_b^T \cdot w_H) v_b$$

- Add the solution from null space to the solution from range:

$$w = w_R + w_N$$



Materials and Methods

Prior Truncated Singular Value Decomposition (PTSVD)

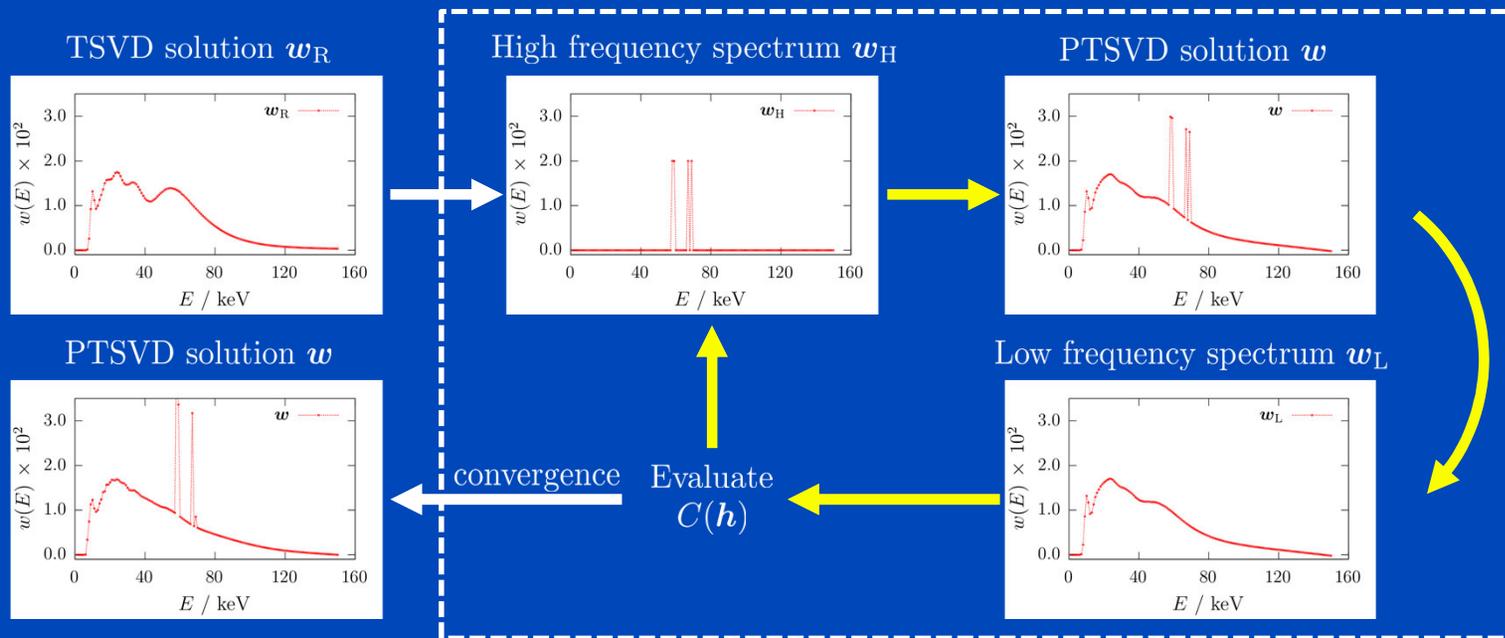
- We model the prior spectrum:
- Cost function

$$w_H(h) = \sum_{p=1}^P h_p e_p$$

$$C(h) = \underbrace{\|w_L(h) \wedge 0\|_2^2}_{\text{Non-negativity}} + \lambda \underbrace{\|\nabla \cdot w_L(h)\|_2^2}_{\text{Smoothness}}$$

$$w_L(h) = w(h) - w_H(h)$$

- Iteration schema:



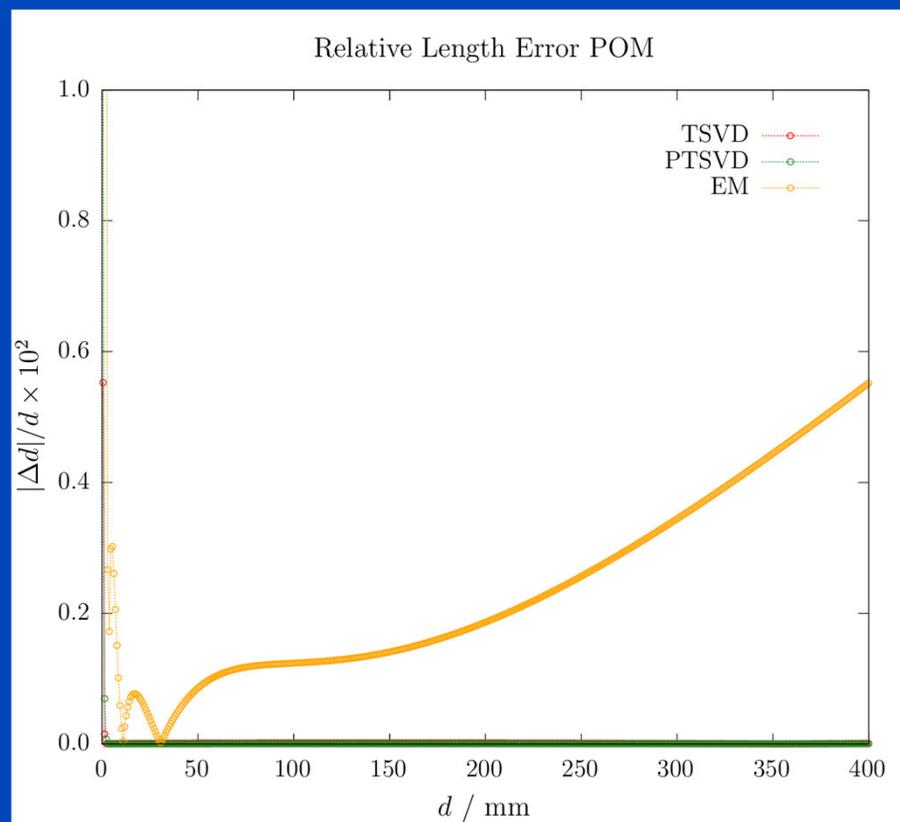
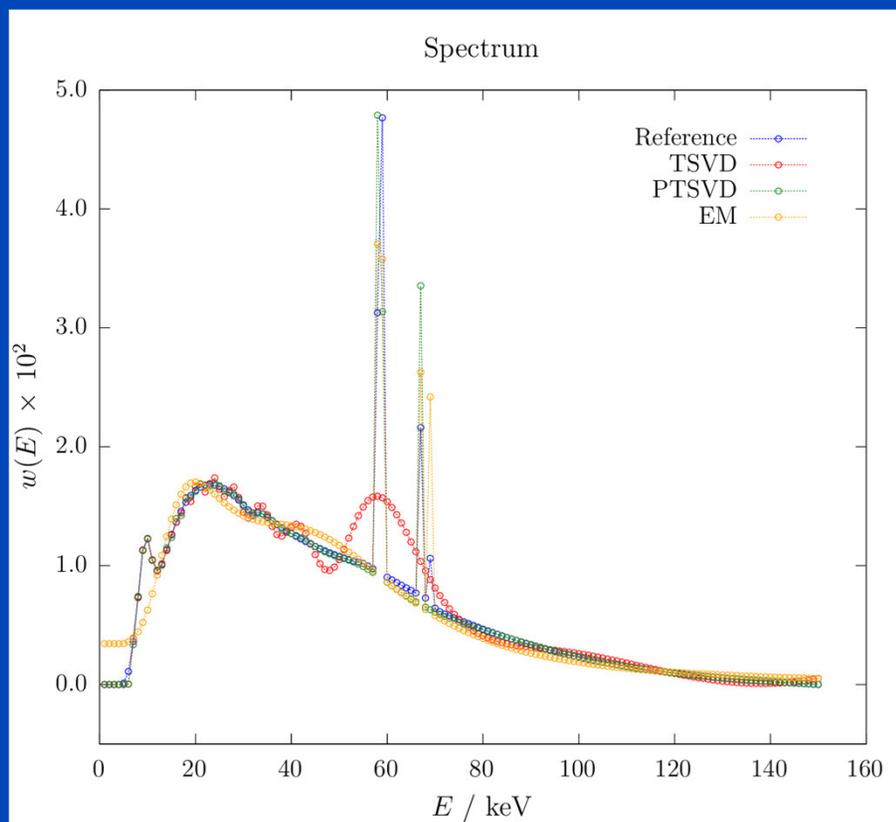
Materials and Methods

Simulation / Measurement Study

- **Simulation conditions:**
 - 150 kV tungsten target spectrum simulated according to Tucker et al.
 - Spectrum estimation from 28 aluminum (Al) attenuators with lengths ranging from 0.5 mm to 132.5 mm
 - Poisson noise is added to the Al transmission data for varying numbers of incident photons N_0
 - Noiseless simulations of polyoxymethylene (POM) with continuous attenuation length for validation
- **Measurement conditions:**
 - Experimental setup consisting of a 150 kV transmission x-ray tube and a flat detector
 - 28 measurements of Al and POM attenuators with attenuation lengths ranging from 0.5 mm to 132.5 mm
 - Material for spectrum estimation: Al
 - Material for spectrum validation: POM

Results

Noiseless Simulated Data

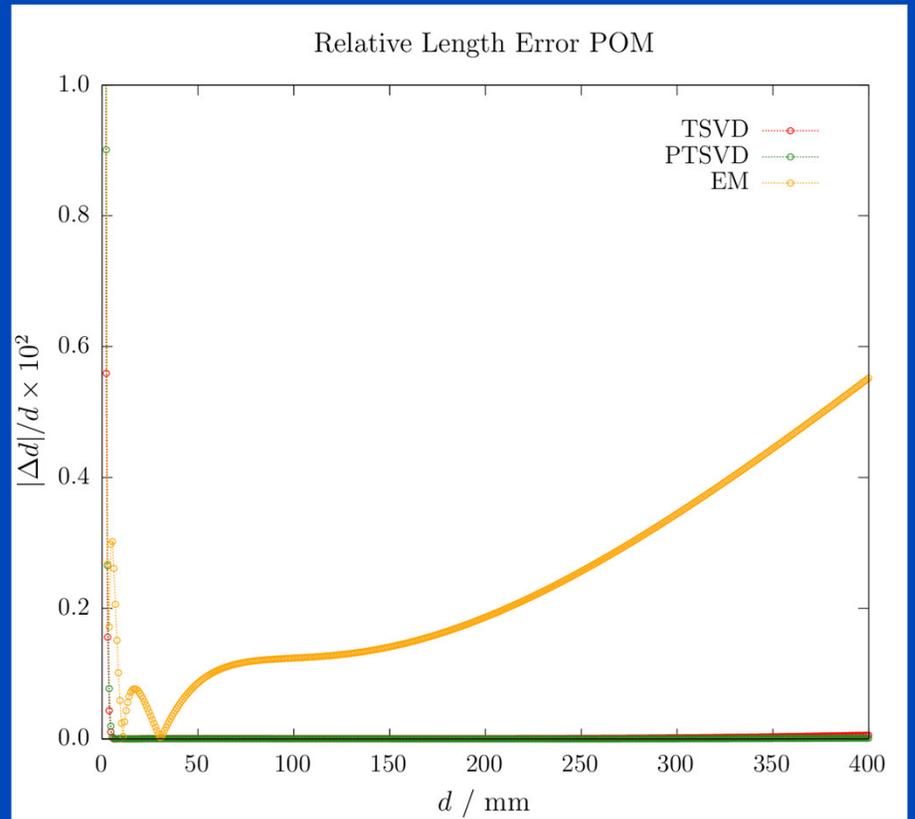
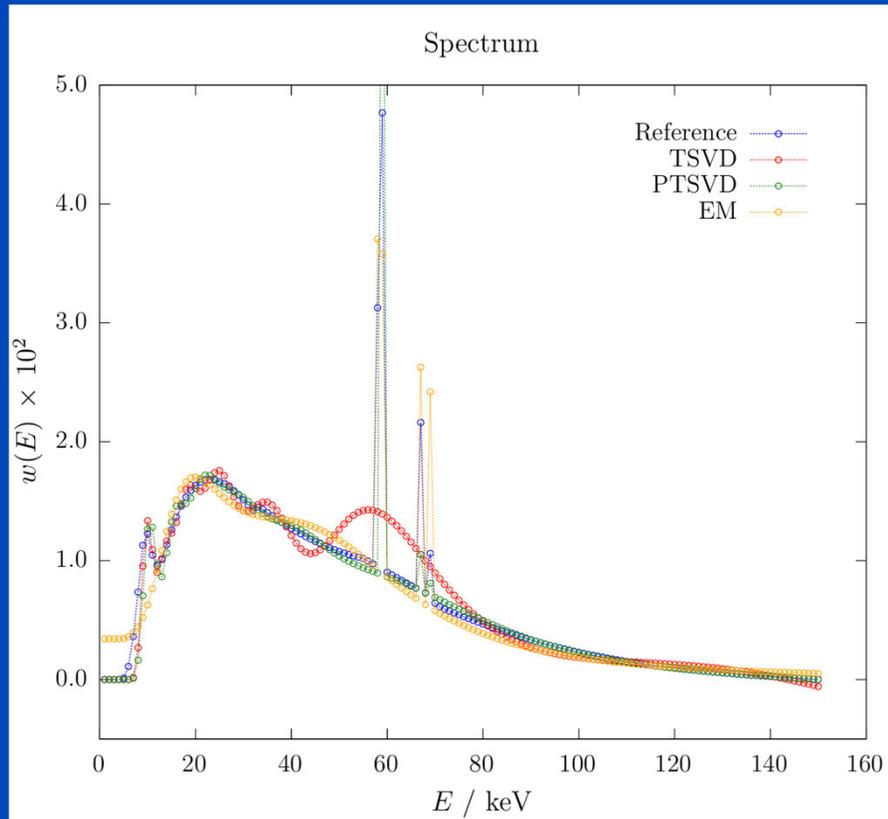


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Results

Noisy Simulated Data

$N_0 = 1 \times 10^{12}$

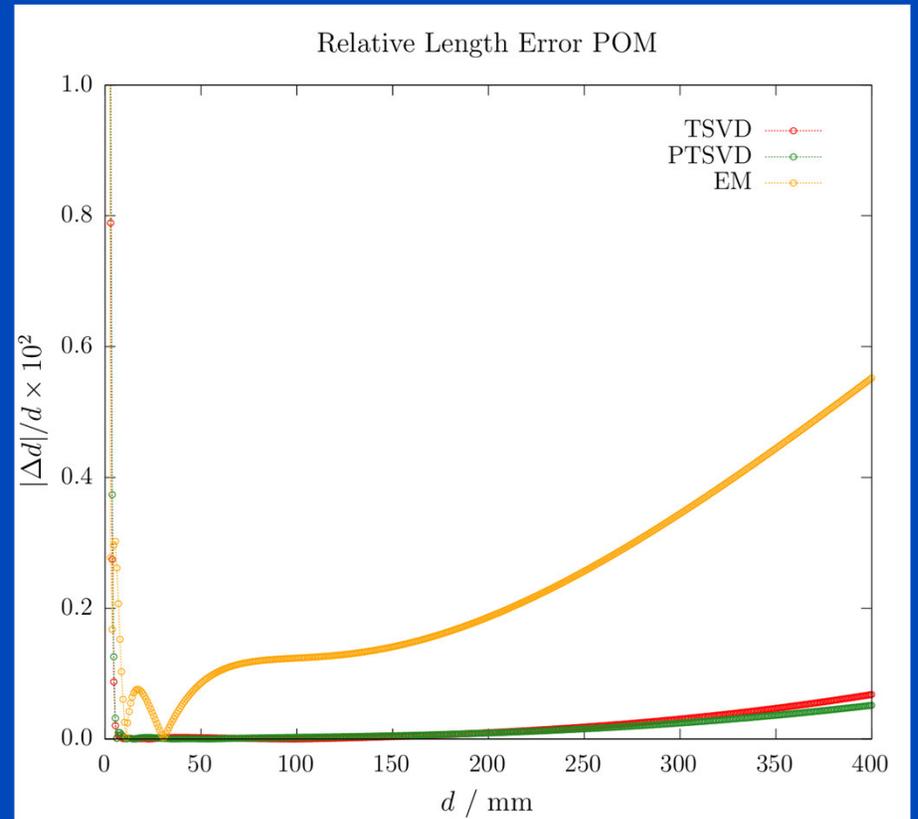
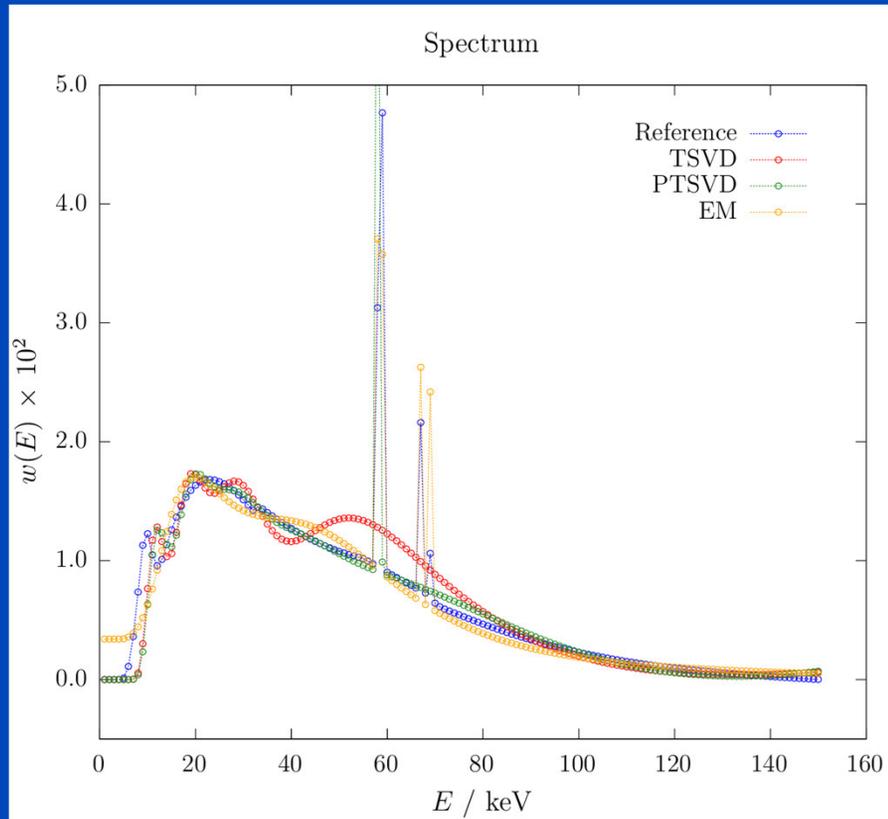


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Results

Noisy Simulated Data

$N_0 = 1 \times 10^{10}$

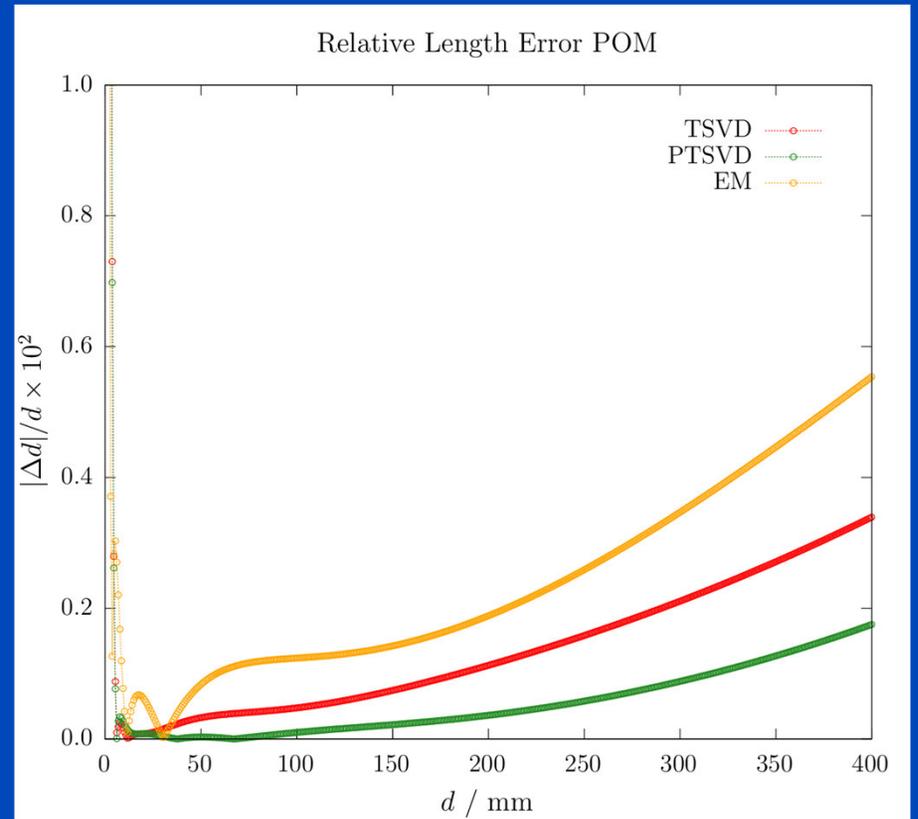
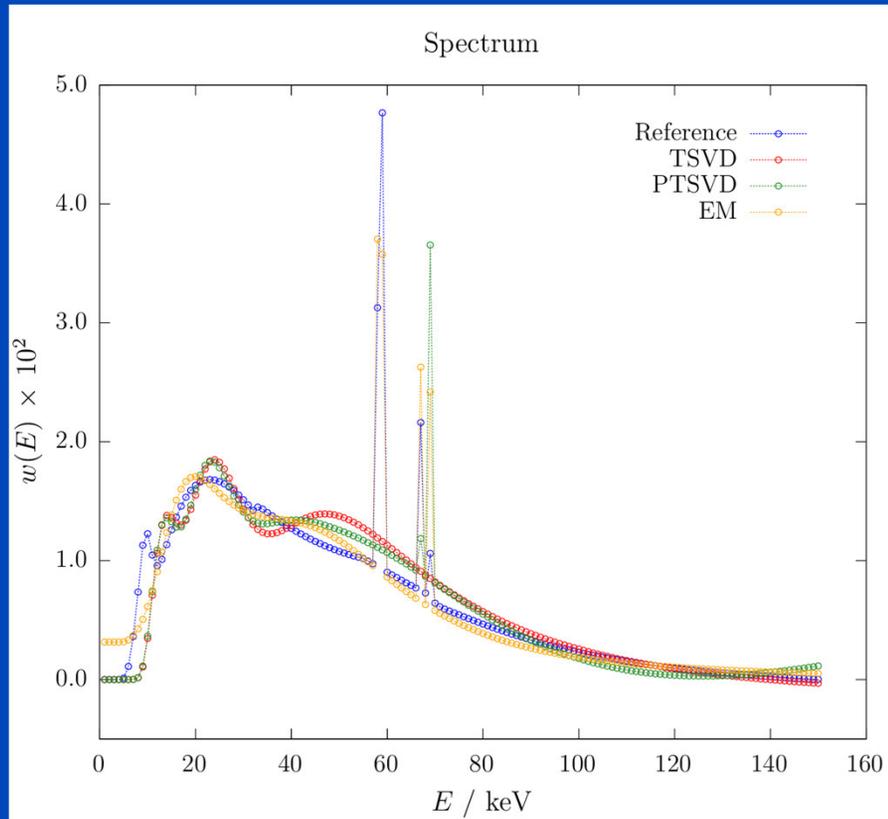


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Results

Noisy Simulated Data

$N_0 = 1 \times 10^8$

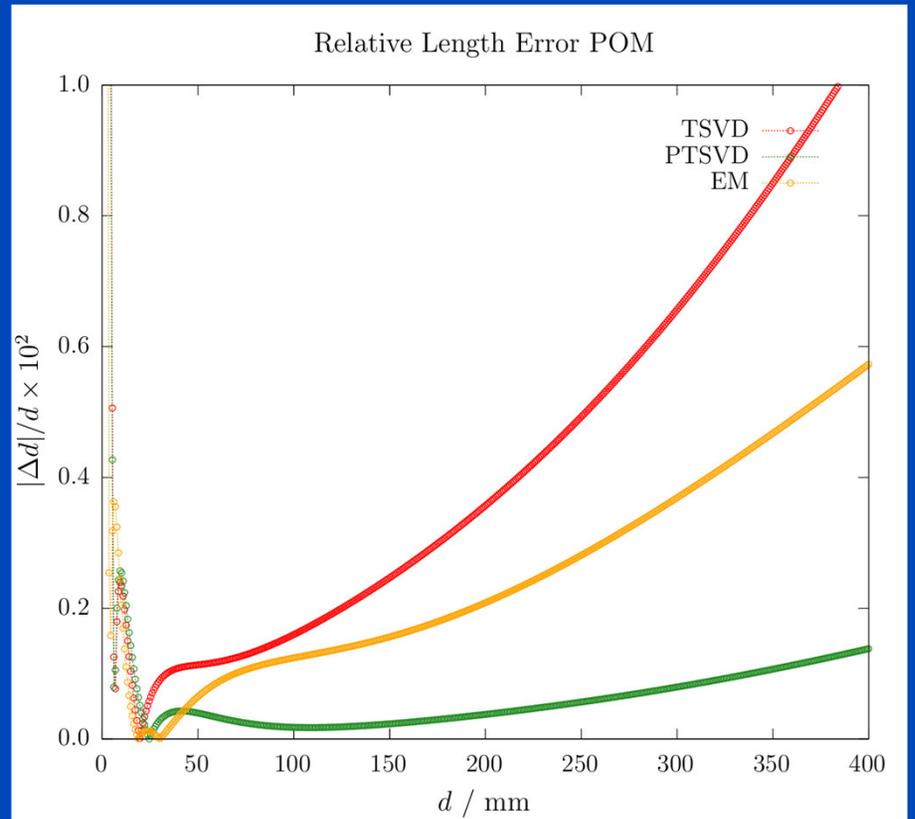
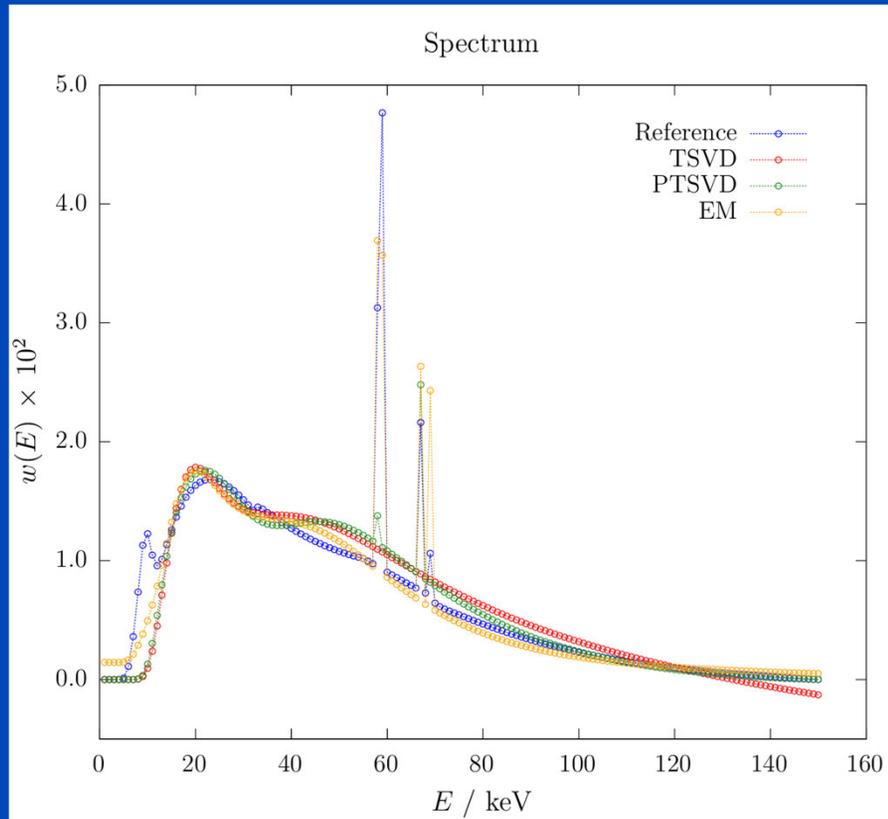


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Results

Noisy Simulated Data

$N_0 = 1 \times 10^6$

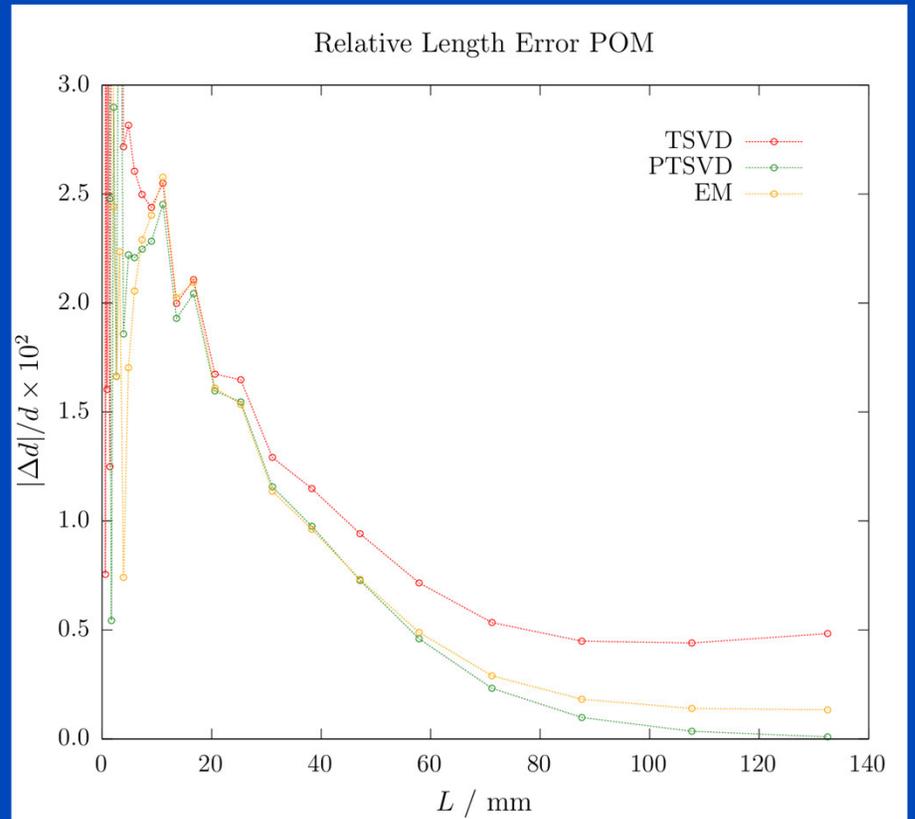
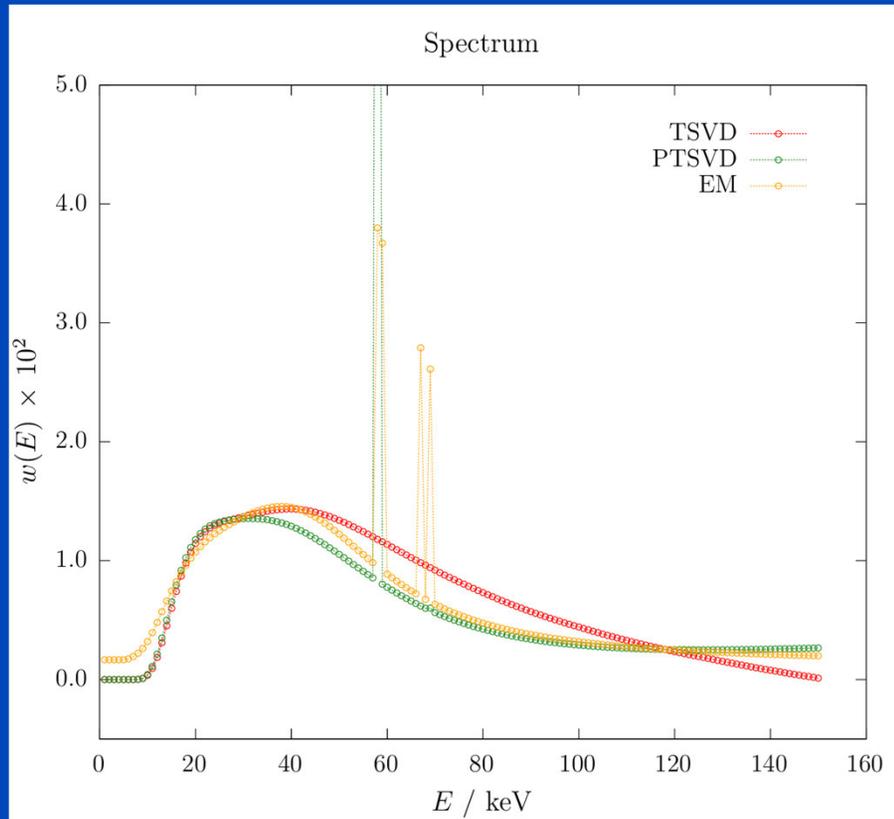


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Results

Measured Data

$N_0 \approx 1 \times 10^{10}$



$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

Conclusion and Discussion

- PTSVD overcomes the limitations of TSVD by incorporating prior information about the statistical nature of the transmission data and about the high frequency components of the spectrum.
- PTSVD is less prone to noise compared to TSVD.
- Simulations show that for accurate transmission data PTSVD leads to smaller length errors compared to EM.
- Effects that limit the accuracy of transmission measurements: quantum noise, electronic noise, scattered radiation, image lag, quantization errors, dynamic range, ...

Thank You!

This study was supported by AiF grant KF2301007NT3.

This presentation will soon be available at www.dkfz.de/ct.

Job opportunities through DKFZ's international PhD or Postdoctoral Fellowship programs (www.dkfz.de), or directly through Marc Kachelrieß (marc.kachelriess@dkfz.de).

Parts of the reconstruction software were provided by RayConStruct[®] GmbH, Nürnberg, Germany.